


INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 60188-555		SERIAL NO. Divisional of Appln. Serial No. 10/122,368	
				APPLICANT Yoshinao HARADA			
				FILING DATE June 25, 2003		GROUP Not yet assigned	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
PS		US 6,013,553	01/2000	WALLACE et al.			
R		US 6,521,911 B2	2/2003	PARSONS et al.			
PC		US 2002/0043666 A1	4/2002	PARSONS et al.			
		US					
		US					
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		US					
		US					
		US					
		US					
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number & Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
PC		EP 0143700 A2	6/1985	BAUDRANT et al.		Yes	No
PC		EP 0077200 A2	4/1980	KATO et al.			
PC		WO 02/09167 A3	1/2002	PARSONS			
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
FO		CHAMBERS and PARSONS, "Yttrium silicate formation on silicon: Effect of silicon preoxidation and nitridation on interface reaction kinetics" Applied Physics Letters 77(15), 9 October 2000, pp. 2385-2387					
PC		GURVITCH et al., "Study of thermally oxidized yttrium films on silicon" Applied Physics Letter 51(12), 21 September 1987, pp. 919-921					
PO		KALKUR et al., "Yttrium oxide based metal-insulator-semiconductor structures on silicon" Thin Solid Films 170, 1989, pp. 185-189.					
PC		PIERSON, HUGH, O., Handbook of Chemical Vapor Deposition, Noyes Publications, Park Ridge, New Jersey pp. 229-230.					
		EXAMINER 			DATE CONSIDERED 08/09/03		

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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